

PRODUCT SUMMARY

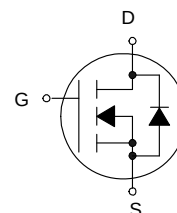
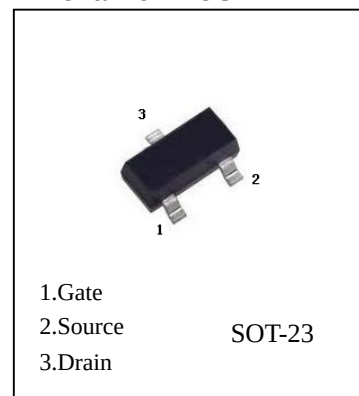
V_{DS} (V)	$R_{DS(on)}$ (Ω)	I_D (A) ^a	Q_g (Typ.)
40	0.042 at $V_{GS} = 10$ V	5.6	2.9 nC
	0.051 at $V_{GS} = 4.5$ V	5.1	

APPLICATIONS

- DC/DC Converters
- Load Switch
- Portable and Consumer Applications

SI2318

N-Channel MOSFET


ABSOLUTE MAXIMUM RATINGS ($T_A = 25$ °C, unless otherwise noted)

Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V_{DS}	40	V
Gate-Source Voltage		V_{GS}	± 20	
Continuous Drain Current ($T_J = 150$ °C)	$T_C = 25$ °C	I_D	5.6 ^a	A
	$T_C = 70$ °C		4.5	
	$T_A = 25$ °C		4.3 ^{b, c}	
	$T_A = 70$ °C		3.5 ^{b, c}	
Pulsed Drain Current		I_{DM}	20	A
Continuous Source-Drain Diode Current	$T_C = 25$ °C	I_S	1.75	
	$T_A = 25$ °C		1.04 ^{b, c}	
Maximum Power Dissipation	$T_C = 25$ °C	P_D	2.1	W
	$T_C = 70$ °C		1.3	
	$T_A = 25$ °C		1.25 ^{b, c}	
	$T_A = 70$ °C		0.8 ^{b, c}	
Operating Junction and Storage Temperature Range		T_J, T_{stg}	- 55 to 150	°C
Soldering Recommendations (Peak Temperature)			260	

THERMAL RESISTANCE RATINGS

Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	$t \leq 5$ s	R_{thJA}	80	100	°C/W
Maximum Junction-to-Foot (Drain)	Steady State	R_{thJF}	40	60	

Notes:

a. Based on $T_C = 25$ °C

b. Surface mounted on 1" x 1" FR4 board.

c. $t = 5$ s.

d. Maximum under steady state conditions is 125 °C/W.

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SPECIFICATIONS (T _J = 25 °C, unless otherwise noted)						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	40			V
V _{DS} Temperature Coefficient	ΔV _{DS} /T _J	I _D = 250 μA		39		mV/°C
V _{GS(th)} Temperature Coefficient	ΔV _{GS(th)} /T _J			- 4.7		
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = 250 μA	1.2		2.5	V
Gate-Source Leakage	I _{GSS}	V _{DS} = 0 V, V _{GS} = ± 20 V			± 100	nA
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 40 V, V _{GS} = 0 V			1	μA
		V _{DS} = 40 V, V _{GS} = 0 V, T _J = 70 °C			10	
On-State Drain Current ^a	I _{D(on)}	V _{DS} ≤ 5 V, V _{GS} = 10 V	20			A
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = 10 V, I _D = 4.3 A		0.035	0.042	Ω
		V _{GS} = 4.5 V, I _D = 3.9 A		0.041	0.051	
Forward Transconductance ^a	g _{fs}	V _{DS} = 20 V, I _D = 4.3 A		17		S
Dynamic ^b						
Input Capacitance	C _{iss}	V _{DS} = 20 V, V _{GS} = 0 V, f = 1 MHz		340		pF
Output Capacitance	C _{oss}			60		
Reverse Transfer Capacitance	C _{rss}			30		
Total Gate Charge	Q _g	V _{DS} = 20 V, V _{GS} = 10 V, I _D = 4.3 A		5.8	9	nC
		V _{DS} = 20 V, V _{GS} = 4.5 V, I _D = 4.3 A		2.9	6	
Gate-Source Charge	Q _{gs}			1.1		
Gate-Drain Charge	Q _{gd}			0.9		
Gate Resistance	R _g	f = 1 MHz	0.6	3.3	6.6	Ω
Turn-On Delay Time	t _{d(on)}	V _{DD} = 20 V, R _L = 5.7 Ω I _D ≅ 3.5 A, V _{GEN} = 4.5 V, R _g = 1 Ω		12	20	ns
Rise Time	t _r			50	75	
Turn-Off Delay Time	t _{d(off)}			10	20	
Fall Time	t _f			8	16	
Turn-On Delay Time	t _{d(on)}	V _{DD} = 20 V, R _L = 5.7 Ω I _D ≅ 3.5 A, V _{GEN} = 10 V, R _g = 1 Ω		7	14	
Rise Time	t _r			20	30	
Turn-Off Delay Time	t _{d(off)}			14	21	
Fall Time	t _f			8	16	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			1.75	A
Pulse Diode Forward Current	I _{SM}				20	
Body Diode Voltage	V _{SD}	I _S = 3.5 A, V _{GS} = 0 V		0.85	1.2	V
Body Diode Reverse Recovery Time	t _{rr}	I _F = 3.5 A, dI/dt = 100 A/μs, T _J = 25 °C		15	23	ns
Body Diode Reverse Recovery Charge	Q _{rr}			7	14	nC
Reverse Recovery Fall Time	t _a			11		ns
Reverse Recovery Rise Time	t _b			4		

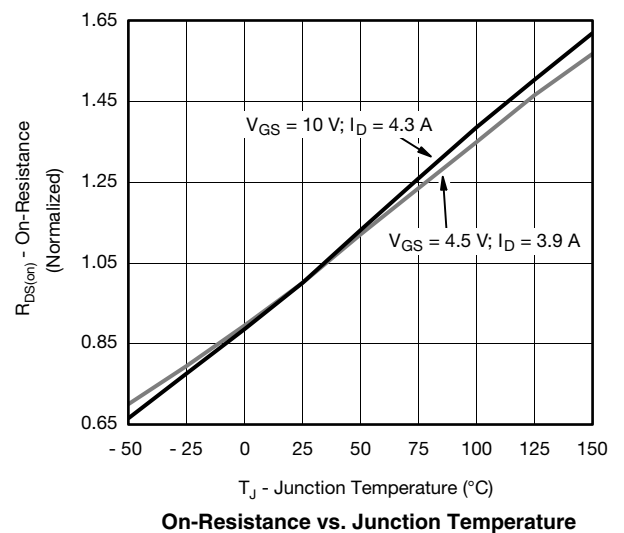
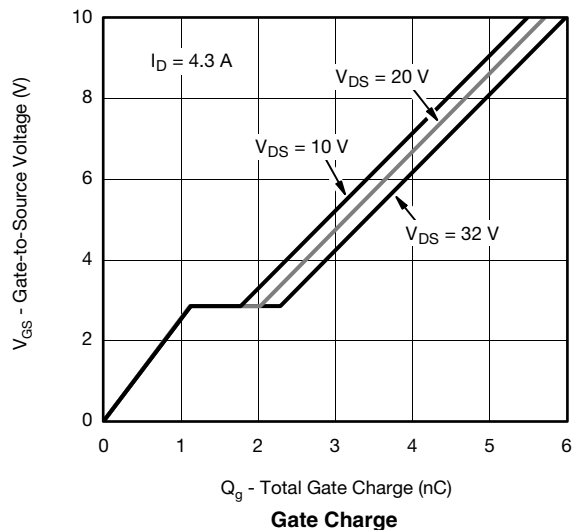
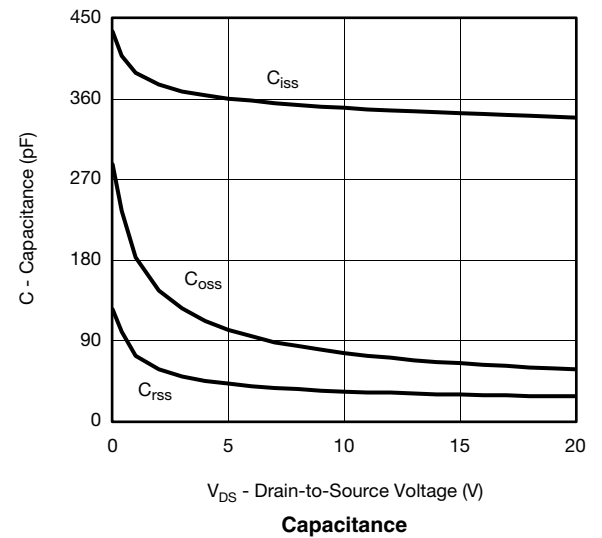
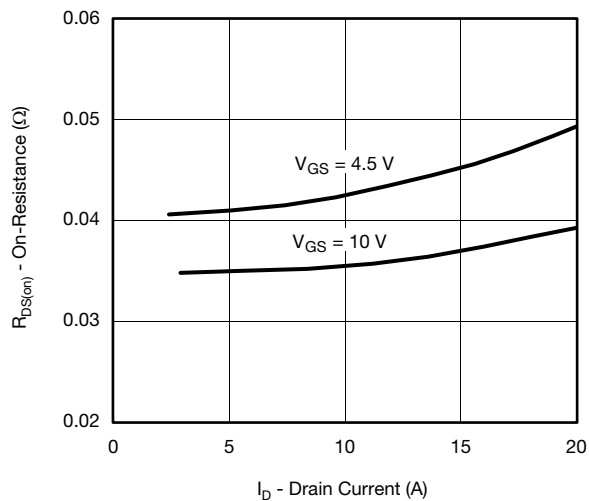
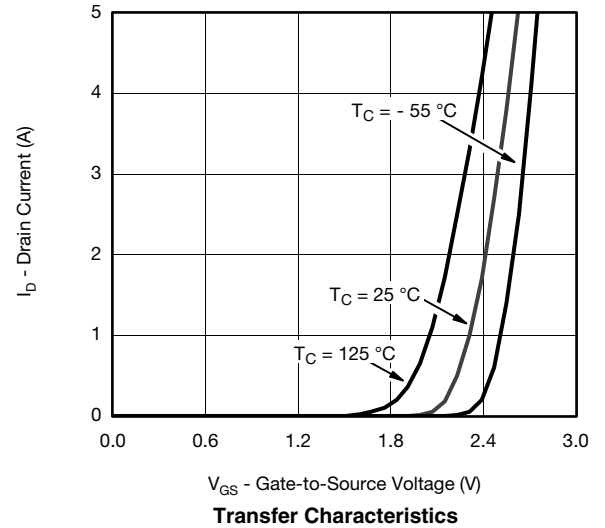
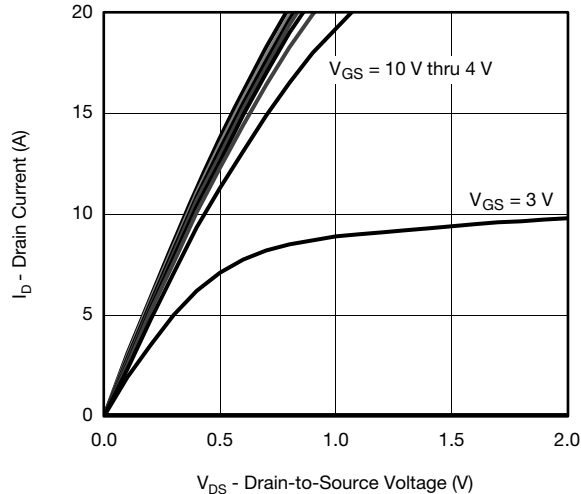
Notes:

a. Pulse test; pulse width $\leq 300\text{ }\mu\text{s}$, duty cycle $\leq 2\%$

b. Guaranteed by design, not subject to production testing.

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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



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